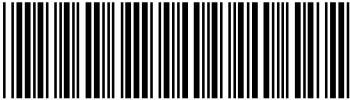


<b>Search Notes</b>  	<b>Application/Control No.</b>  10786164	<b>Applicant(s)/Patent Under Reexamination</b>  BEAN ET AL.
	<b>Examiner</b>  Chin-Shue, Alvin C	<b>Art Unit</b>  3634

SEARCHED			
Class	Subclass	Date	Examiner
182	18	4/27/07	acs
update		10/10/07	acs
update		7/9/08	acs

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner